

AMENDMENTS TO THE CLAIMS:

This listing of the claims will replace all prior versions, and listings, of the claims in this application:

Please cancel claims 48 and 49 without prejudice or disclaimer.

Listing of Claims:

1.-18. (Canceled)

19. (Currently Amended) A diffusion barrier comprising a plurality of stacked sub-layers, each sub-layer having a thickness of about 0.4 to about 4.5 nanometers (nm) where interfaces between the sub-layers ~~to~~ inhibit the formation of a crystalline lattice, wherein the plurality of stacked sub-layers are arranged collectively to inhibit diffusion of a chemical species through the diffusion barrier, wherein a successive sub-layer comprises a different material from a material that comprises a preceding sub-layer and the different materials selected to comprise the sub-layers are substantially immiscible and exhibit mutual adhesion, and ~~the overall thickness of the diffusion barrier is between about 30 and 50 angstroms,~~ where the plurality of stacked sub-layers are three or more stacked sub-layers, wherein the stacked sub-layers are of alternating composition, where a layer consist of alternating sub-layers of tantalum (Ta) alternates with a layer of ~~and~~ one of the following metals: copper (Cu), scandium (Sc), yttrium (Y), and lanthanum (La).

20-37. (Canceled).

38. (Currently Amended) A multilayer diffusion barrier comprised of interfaces and atomically thin films in which surface adhesion of each interface inhibits the formation of a lattice in the films, inhibiting diffusion across the barrier, wherein thickness of each film is in a range of about 0.4 to about 4.5 nm, wherein a successive film comprises a different material from a material that comprises a preceding film, wherein the atomically thin films are at least three in number, wherein the stacked atomically thin films are ~~consist of~~ alternating atomically thin films of tantalum (Ta) and one of the following metals: copper (Cu), scandium (Sc), yttrium (Y), and lanthanum (La).

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39. (Canceled)

40. (Canceled)

41. (Previously Presented) A multilayer diffusion barrier structure comprised of three or more sub-layers each having a thickness of about 0.4 to about 4.5 nanometers (nm) and an interface, wherein the interface of each of the sub-layers dominates a lattice formation on the sub-layers, preventing the formation of a lattice and grain boundaries, the multilayer structure being arranged to inhibit diffusion of a chemical species through the structure, wherein a successive sub-layer comprises a different material from a material that comprises a preceding sub-layer, wherein the sub-layers consist of alternating sub-layers of tantalum (Ta) and one of the following metals: copper (Cu), scandium (Sc), yttrium (Y), and lanthanum (La).

42. (Canceled)

43. (Currently Amended) A multilayer diffusion barrier for inhibiting diffusion of chemical species there through, comprising a plurality of stacked amorphous layers, the thickness of each of said films being between about 0.4 to about 4.5 nm, which is predetermined to substantially eliminate work hardening, wherein a successive layer of the plurality of stacked layers comprises a different metal from a metal that comprises a preceding layer of the plurality of stacked layers, wherein the plurality of stacked layers are at least three in number, wherein the plurality of stacked layers are ~~consist of~~ alternating layers of tantalum (Ta) and one of the following metals: copper (Cu), scandium (Sc), yttrium (Y), and lanthanum (La).

44. (Currently Amended) A diffusion barrier having a multilayer structure comprised of at least three films forming a bond at an interface between each film, each film having a thickness of about 0.4 to about 4.5 nm, wherein the interface dominates a lattice formation, inhibiting the formation of a lattice and grain boundaries, wherein a successive film comprises a different material from a material that comprises a preceding film, ~~wherein at least one of the films comprises a dielectric material~~, wherein the at least three

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films are ~~consist of~~ alternating films of tantalum (Ta) and one of the following metals: copper (Cu), scandium (Sc), yttrium (Y), and lanthanum (La).

45. (Canceled)

46. (Canceled)

47. (Previously Presented) The multilayer structure of claim 44, wherein the at least two materials exhibit mutual adhesion and are substantially immiscible.

48. (Canceled).

49. (Canceled).

50. (Canceled).

51. (Canceled).

52. (Previously Presented) The multilayer structure of claim 44, having flexibility and inhibited work hardening.

53. (Previously Presented) The multilayer structure of claim 44, which is a diffusion barrier between two materials that are otherwise capable of combining chemically or between a layer and a surface capable of chemically combining with the layer.

54-60. (Canceled).

61. (Previously Presented) A diffusion barrier as in claim 19, where the plurality of sub-layers are between three and ten in number.

62-65. (Canceled).